



N-Channel

Enhancement Mode Power MOSFET

General Description

The UV1404R uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

Features

- $V_{DS}=40V$; $I_D=190A @ V_{GS}=10V$;
 $R_{DS(ON)} < 4 m\Omega$ @ $V_{GS} = 10V$
- Special process technology for high ESD capability
- Special designed for Convertors and power controls
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high EAS
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply



TO-220-3L top view



Schematic diagram

Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
UV1404R	UV1404R	TO-220	-	-	Y

Table 1. Absolute Maximum Ratings (TA=25°C)

Parameter	Symbol	Value	Unit
Drain-Source Voltage ($V_{GS}=0V$)	V_{DS}	40	V
Gate-Source Voltage ($V_{DS}=0V$)	V_{GS}	± 25	V
Drain Current (DC) at $T_c=25^\circ C$	$I_D(DC)$	190	A
Drain Current (DC) at $T_c=100^\circ C$	$I_D(DC)$	130	A
Drain Current-Continuous@ Current-Pulsed ^(Note 1)	$I_{DM}(\text{pulse})$	430	A
Maximum Power Dissipation($T_c=25^\circ C$)	P_D	230	W
Derating factor		1.33	W/°C
Single pulse avalanche energy ^(Note 2)	E_{AS}	1000	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	°C

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2.EAS condition: $T_j=25^\circ C, V_{DD}=28V, V_G=10V, L=1mH, R_g=25\Omega$;



Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Note2)	R _{thJC}	0.75	°C/W

Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

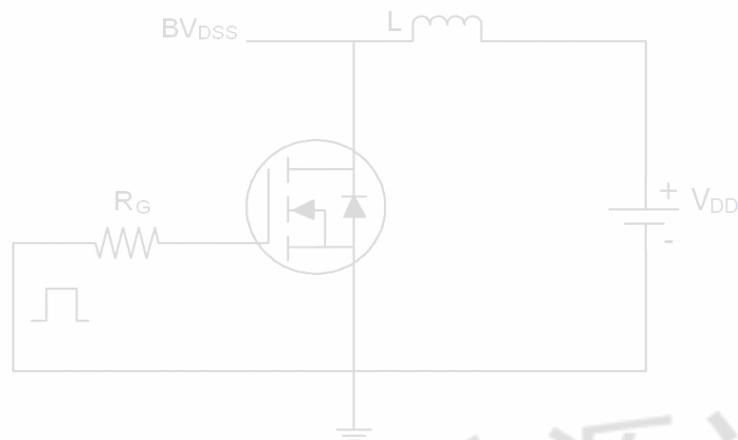
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	40	-	-	V
Zero Gate Voltage Drain Current(Tc=25°C)	I _{DSS}	V _{DS} =-24V, V _{GS} =0V		1		μA
Gate-Body Leakage Current	I _{DSS}	V _{GS} =±25V, V _{DS} =0V			±100	μA
On Characteristics (Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2	-	4	V
Drain-Source On-State Resistance	R _{Ds(ON)}	V _{DS} =10V, I _D =40A	3	4		mΩ
Dynamic Characteristics						
Forward Transconductance	G _{FS}	V _{DS} =25V, I _D =40A	50			S
Input Capacitance	C _{iss}	V _{DS} =30V, V _{GS} =0V, F=1.0MHz		5000		PF
Output Capacitance	C _{oss}			860		PF
Reverse Transfer Capacitance	C _{rss}			480		PF
Total Gate Charge	Q _g			106		nC
Gate-Source Charge	Q _{gs}	V _{DS} =30V, I _D =40A, V _{GS} =10V		20		nC
Gate-Drain Charge	Q _{gd}			35		nC
Switching times						
Turn-on Delay Time	t _{d(on)}	V _{DD} =30V, I _D =1A, R _L =30Ω		34	50	nS
Turn-on Rise Time	t _r			30	46	nS
Turn-Off Delay Time	t _{d(off)}	V _{GS} =10V, R _G = 6 Ω		124	200	nS
Turn-Off Fall Time	t _f			64	116	nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}				40	A
Forward on voltage ^(Note 3)	V _{SD}	T _j =25°C, I _{SD} =20A, V _{GS} =0V		0.8	1.3	V
Reverse Recovery Time ^(Note 1)	t _{rr}	T _j =25°C, I _F =40A, di/dt=100A/μs		74		nS
Reverse Recovery Charge	Q _{rr}			140		nC
Forward Turn-on Time	t _{on}	Intrinsic turn-on time is negligible(turn-on is dominated by L _s +L _d)				

Notes 3.Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%, R_G =25 Ω, Starting T_j=25°C

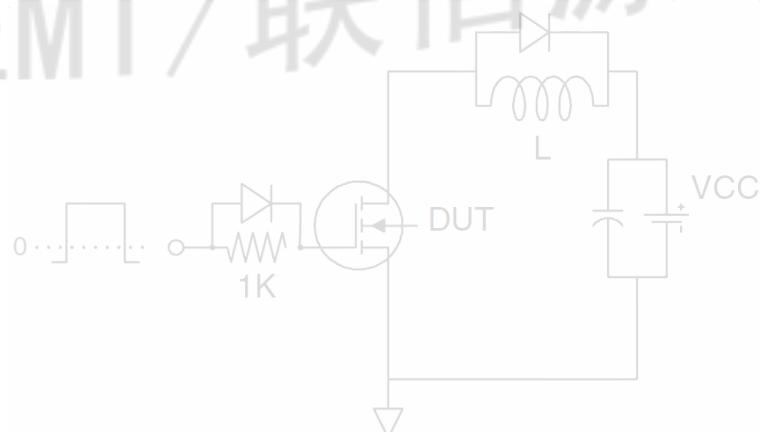


Test circuit

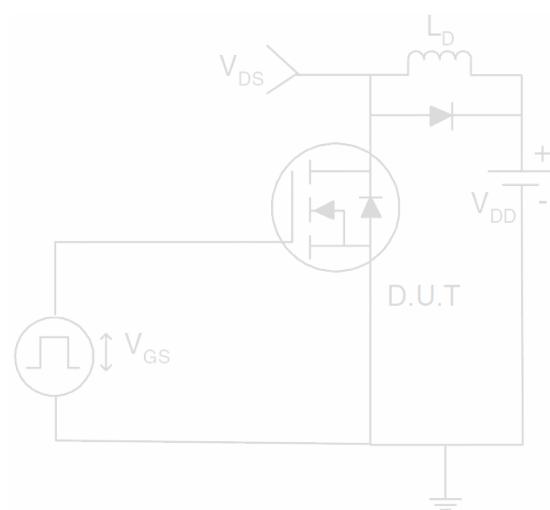
1) E_{AS} test Circuits



2) Gate charge test Circuit:

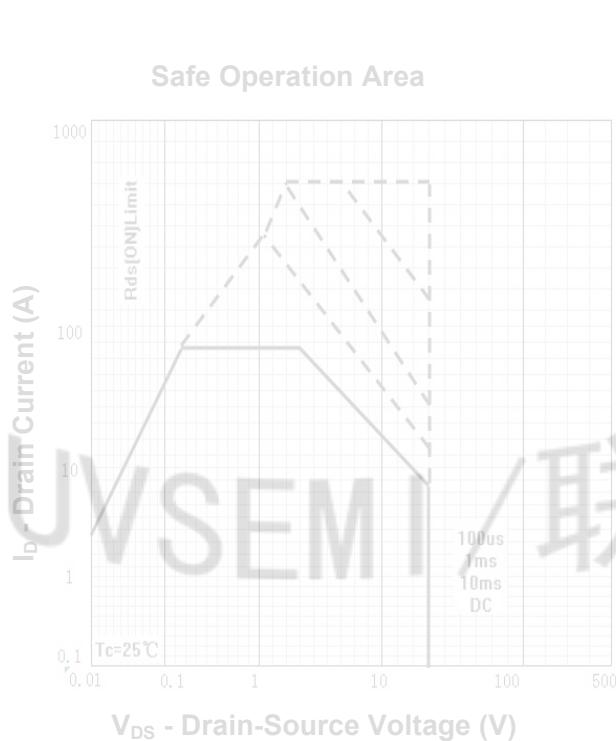


3) Switch Time Test Circuit:

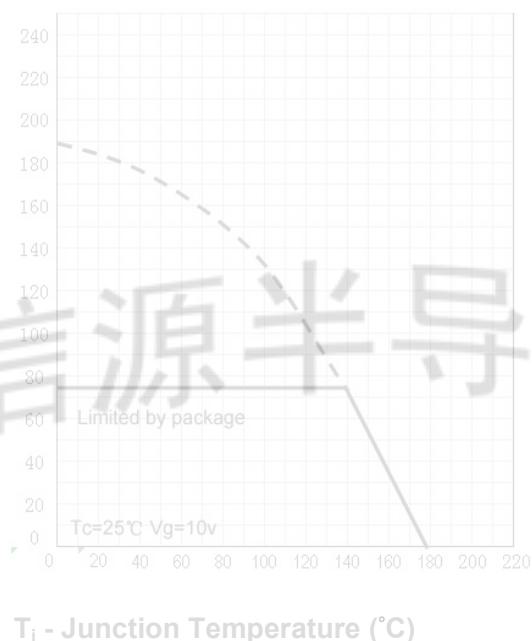




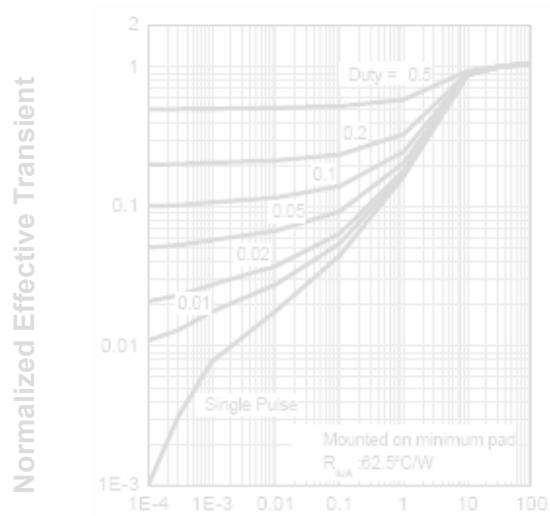
Typical Characteristics



Drain Current

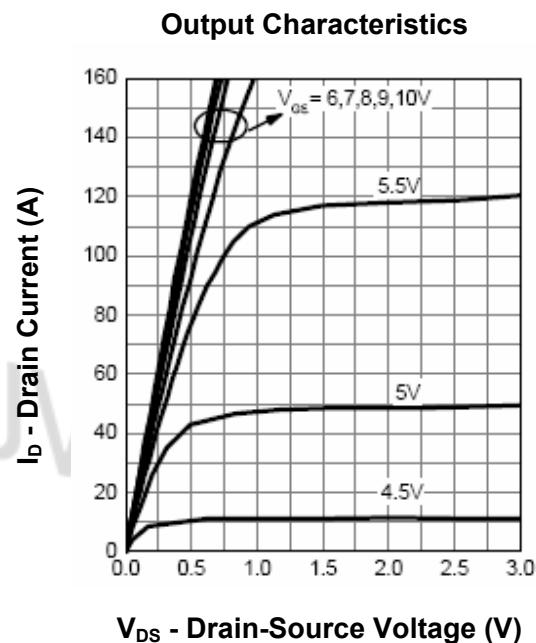
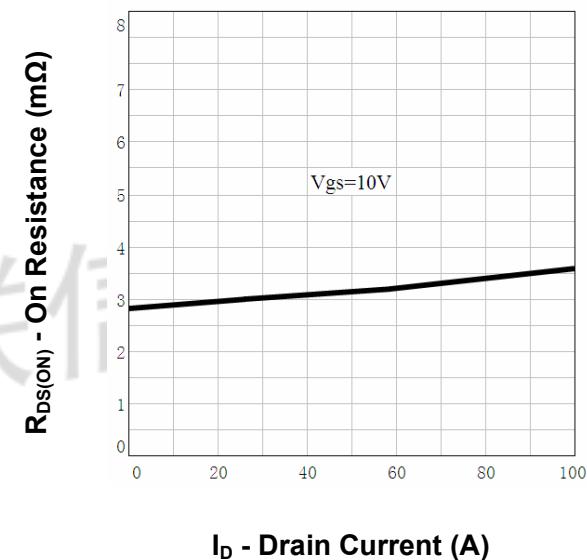
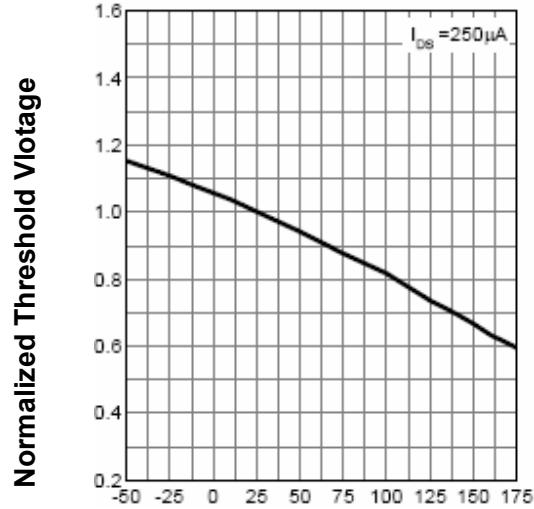
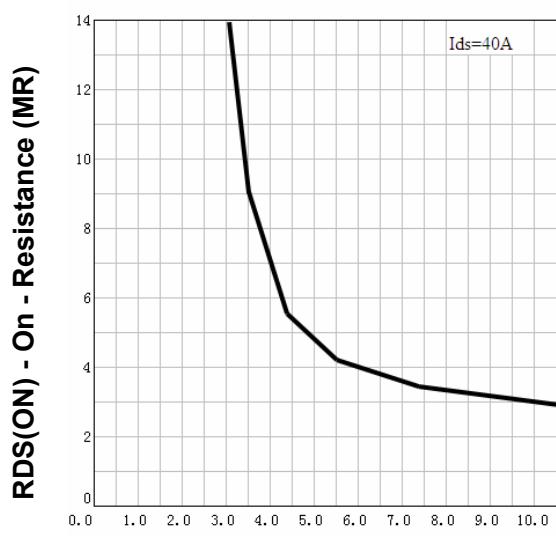


Thermal Transient Impedance



Square Wave Pulse Duration (sec)

Typical Characteristics (Cont.)

**Drain-Source On Resistance****Drain-Source On Resistance****Gate Threshold Voltage****VGS - Gate - Source Voltage (V)****Tj - Junction Temperature (°C)**

Typical Characteristics (Cont.)

